

Approved : Takuya Mori

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No.	Test item	Conditions	Conditions of acceptability	Result
1	High temp./overload test	(1) Input Max.voltage, Min.voltage (2) Overload (3) Baseplate temp. 85°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1)Power supply is not failed.	O.K.
2	High voltage input test	(1) Input (DC220V) (2) Rated output (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)No smoke, no fire.	O.K.
3	Low voltage input test	(1) Input Min. regulation voltage (2) Rated output (3) Baseplate temp. 85°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1)Power supply is not failed.	O.K.
4	Input ON/OFF test	(1) Input Max.voltage (DC160V) T= 2sec Duty= 50% (2) Rated output (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Power supply is not failed. (2)The surge current of each components should not exceed the rated value.	O.K.
5	Output ON/OFF test	(1) Rated input (DC110V) (2) Output 0%←→100% T= 2sec Duty= 50% (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Power supply is not failed.	O.K.
6	Output-short start test	(1) Rated input (DC110V) (2) Output Short start (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1)Power supply is not failed.	O.K.
7	Output short test	(1) Rated input (DC110V) (2) Output Short (3) Ambient temp. 25±10°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1)Power supply is not failed.	O.K.
8	Withstand voltage test (High-pot test)	(1) Input Not applied. (2) Ambient temp. 25±10°C (3) The applied voltage is 1.4 times of specifications.	(1)Insulation breakdown , flashover or electric arc is not occurred	O.K.
9	Isolation resistance test	(1) Input Not applied. (2) Ambient temp. 25±10°C	(1)When a regulation voltage is applied, isolation resistance is 1.4 times of specifications.	O.K.
10	Vibration/impact test	Vibration (1)f=10~55Hz : 49.0m/s ² (2)3 minutes period (3)60 minutes along X, Y and Z axis Impact (1)196.1m/s ² 11ms (2)Once each X, Y and Z axis	(1)No degradation of electric characteristics after test. (2)No crack at solder joint. (3)No marked damage of appearance.	O.K.

OSafety testing circuitry

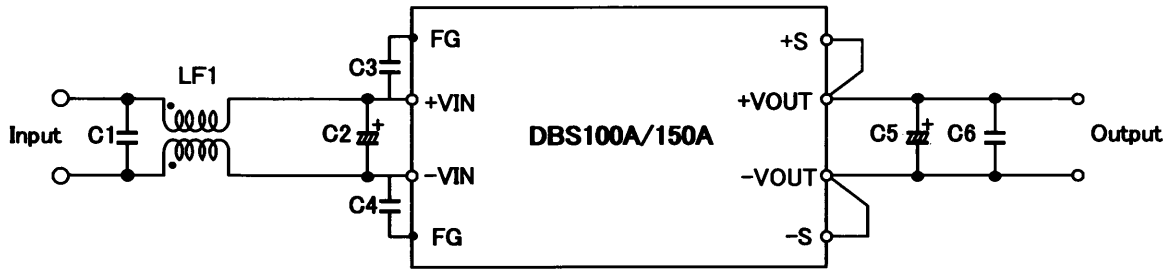


Fig.1 testing circuitry (from No.1 to No.7)

- C1 : 0.1 μ F 250V Film capacitor
- C2 : 47 μ F 250V Electric capacitor
- C3 , C4 : 2200pF 250V Ceramic capacitor
- C5 : 2200 μ F 10V Electric capacitor(DBS100A05)
- : 1000 μ F 25V Electric capacitor (DBS100A13R8/DBS150A12, 15)
- : 470 μ F 35V Electric capacitor (DBS150A24)
- C6 : 0.1 μ F 50V Film capacitor
- LF1 : 1mH 3A Common mode Choke Coil

or equivalent.